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# Error modelling in Bayesian CSEM inversion

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# General error structure in inverse problems

- Model

$$y = F(\mathbf{m}) + \epsilon$$

$F(\mathbf{m})$  = forward model (Maxwell etc, or approximations)

$y$  = measured data (E fields etc)

$\mathbf{m}$  = gridblock resistivities, anisotropy

object-like: locations, surfaces, etc

- Error

$$\epsilon = \epsilon_{\text{instr/proc}} + \epsilon_{\text{env}} + \epsilon_{\text{model}}$$

# Inversion approach

- Bayes

$$P(\mathbf{m}|y) \sim L(y|\mathbf{m})P(\mathbf{m})$$

- Typically;

$$P(\mathbf{m}, \mu, \sigma_n^2 | \mathbf{y}) \sim \frac{e^{-(\mathbf{y} - \mathbf{F}(\mathbf{m}))^T C_d(\sigma_n)^{-1} (\mathbf{y} - \mathbf{F}(\mathbf{m}))/2}}{(2\pi)^{n_d/2} |C_d(\sigma_n)|^{1/2}} \frac{e^{-(\mathbf{m} - \mathbf{m}_p)^T C_p(\mu)^{-1} (\mathbf{m} - \mathbf{m}_p)/2}}{(2\pi)^{n_p/2} |C_p(\mu)|^{1/2}}.$$

- If  $C_d$  “known”...

$$\chi^2 = (\mathbf{y} - \mathbf{F}(\mathbf{m}))^T C_d^{-1} (\mathbf{y} - \mathbf{F}(\mathbf{m})) + (\mathbf{m} - \mathbf{m}_p)^T C_p^{-1} (\mathbf{m} - \mathbf{m}_p)$$

- Objections to Bayes

Often focused on  $P(\mathbf{m})$

Noise structure in  $L(y|\mathbf{m})$  often more questionable/disputable

# Some terminology

Marginal distributions

$$P(m_i|y) = \int P(\mathbf{m}|y) dm_{j \neq i}$$

Model probabilities: ‘evidence’ or ‘marginal model likelihood’

$$P(\mathcal{M}) = \int P(\mathbf{m}|y, \mathcal{M}) d\mathbf{m}$$

Typical approximations for evidence (Laplace)

$$P(\mathcal{M}) \sim |H|^{-1/2} \exp(-\chi^2(\hat{\mathbf{m}})/2)$$

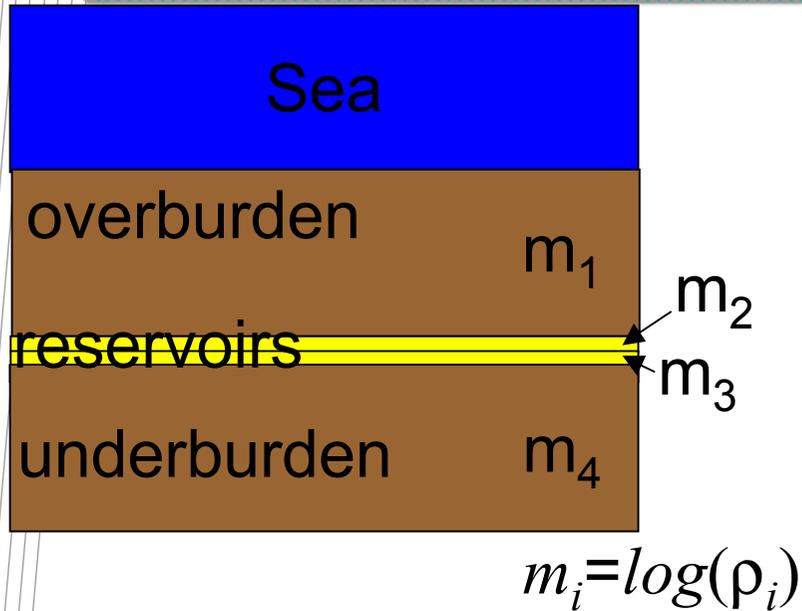
# Posterior Uncertainties

- Linearisation is useful only if the geometry is *extremely* coarse. For finer models,  $F(m)$  has a huge “null-space”. But decisions needed on finer models.
- Approximate posterior distributions from Hessian usually very poor.
- Alternative sampling methods required
  - **Tailored MCMC methods**

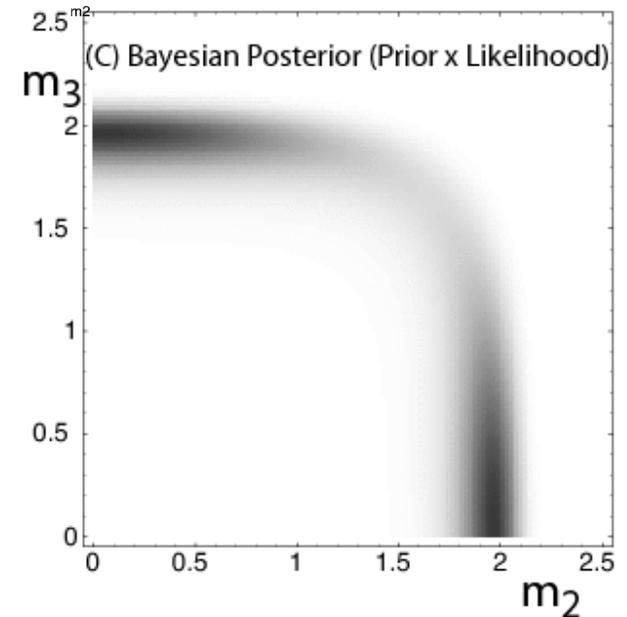
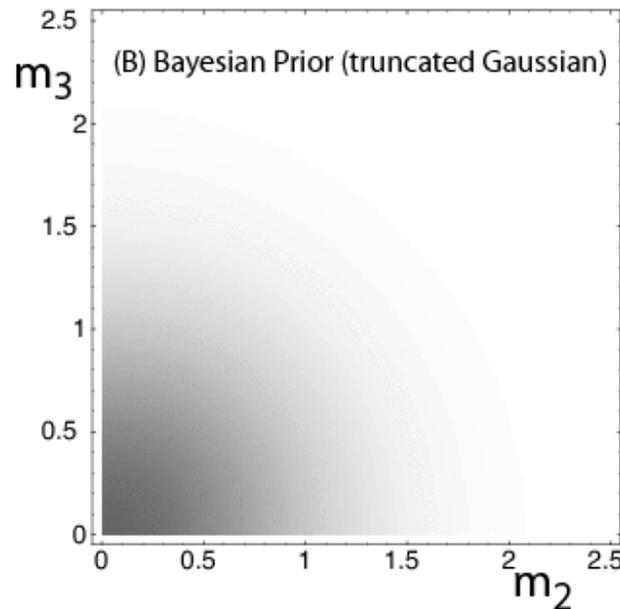
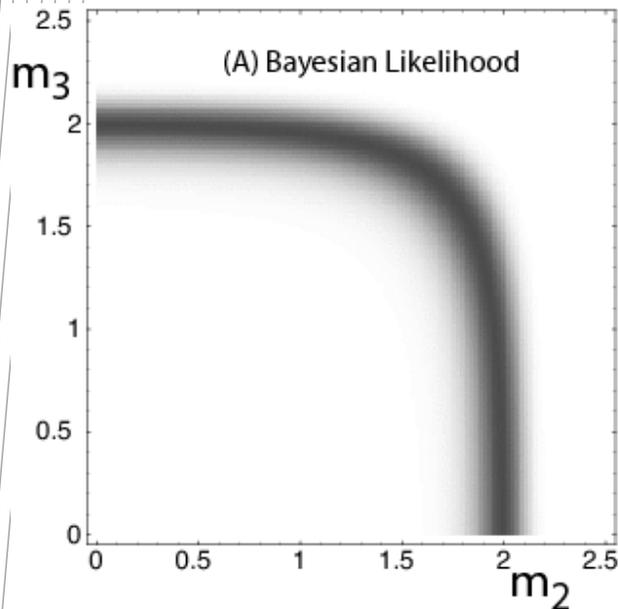
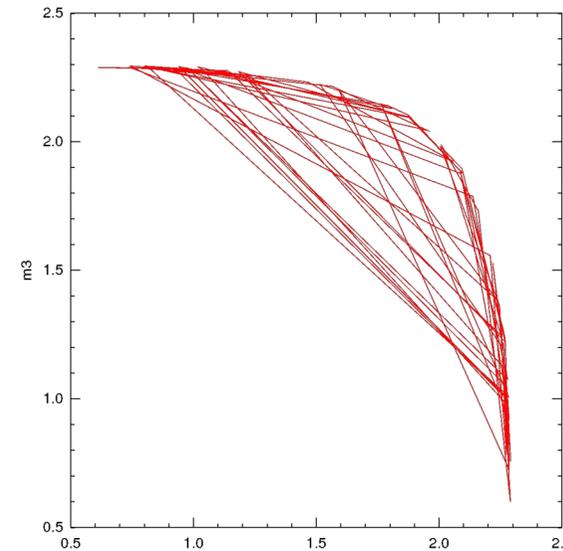
Exhaustive mode enumeration, followed by mixture of:

    - 1) Reversible jump MCMC (diffusion)
    - 2) Mode jumps
    - 3) Big jumps along constant RTP
  - **Bayesianized Parametric Bootstrap**

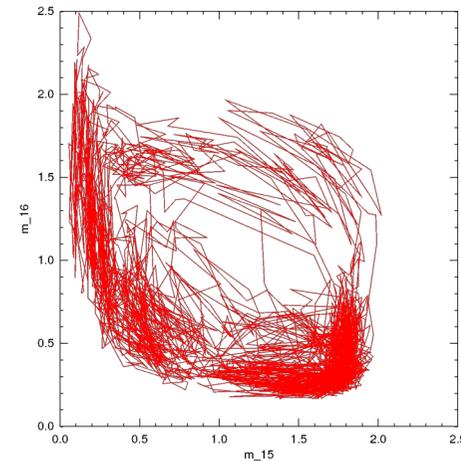
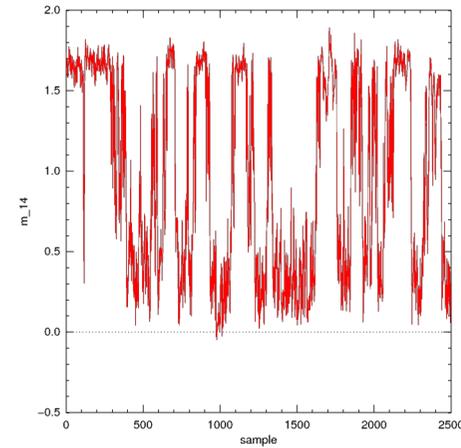
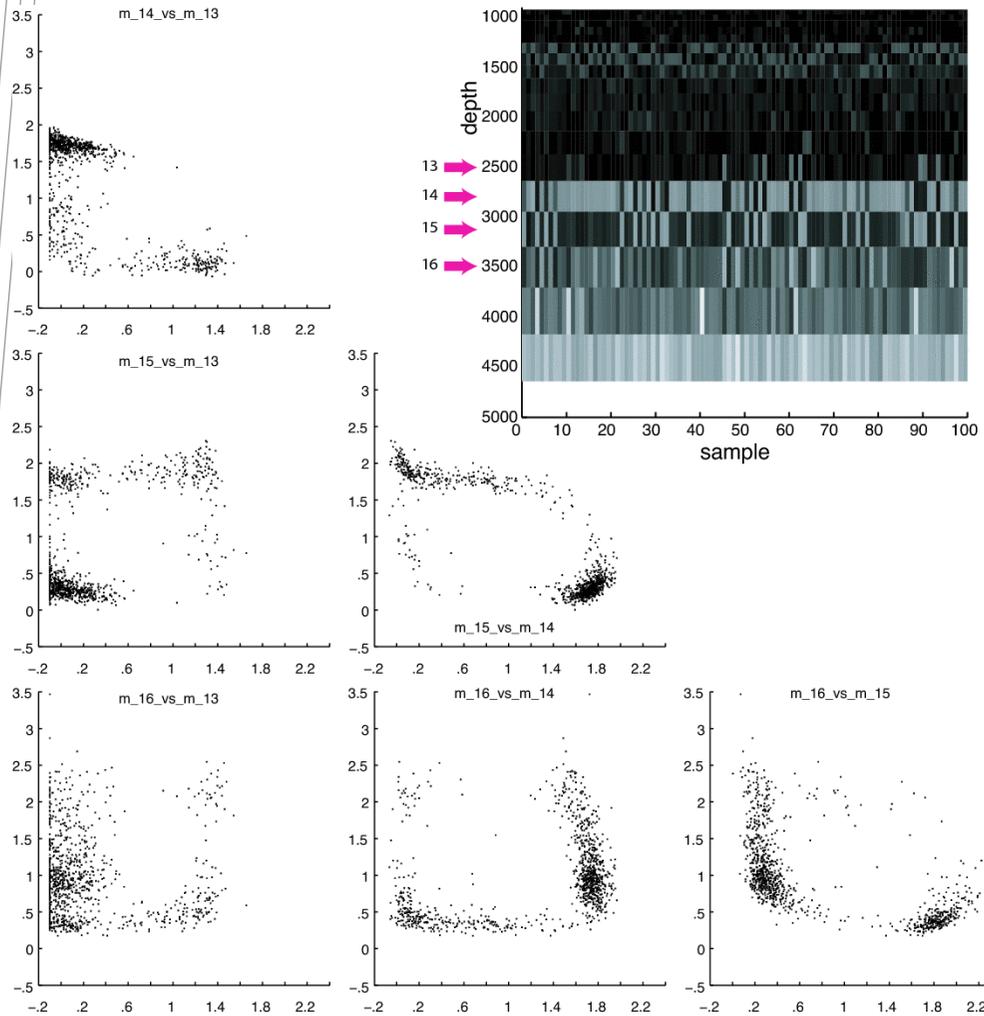
# Illustrative 1D example



Tailored MCMC:



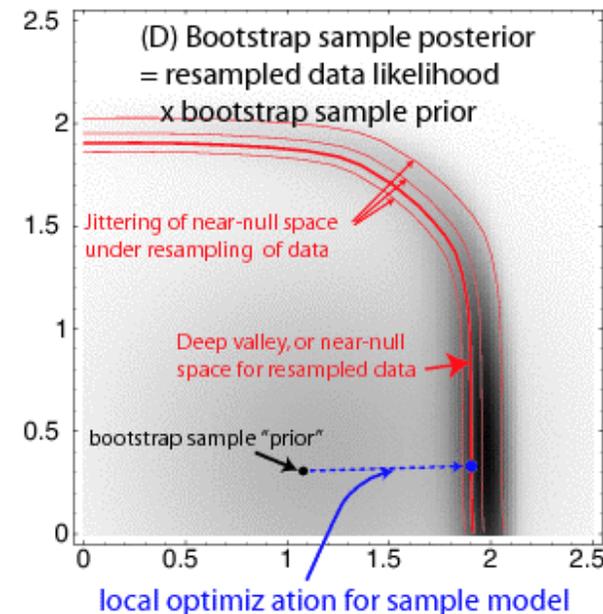
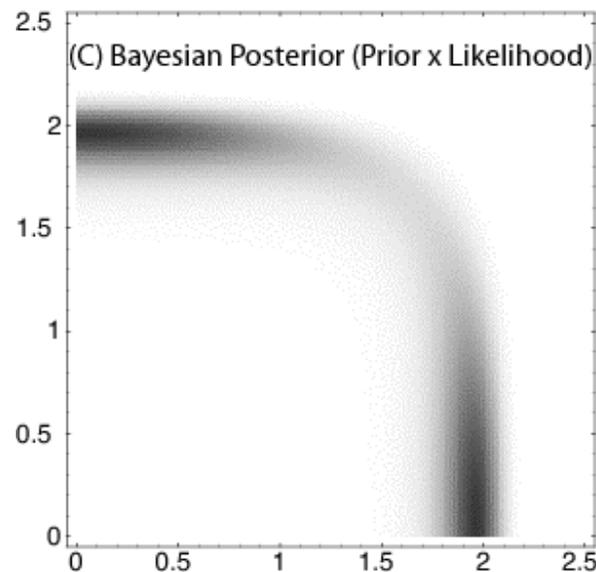
# More complex MCMC example



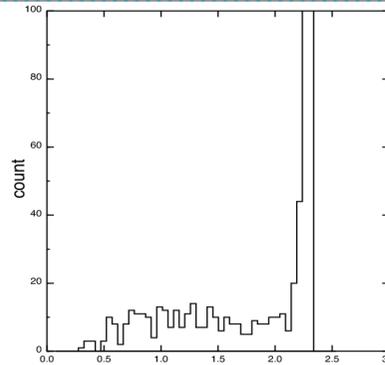
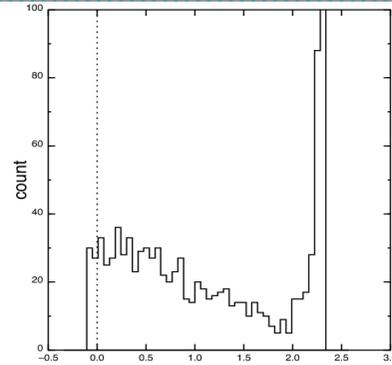
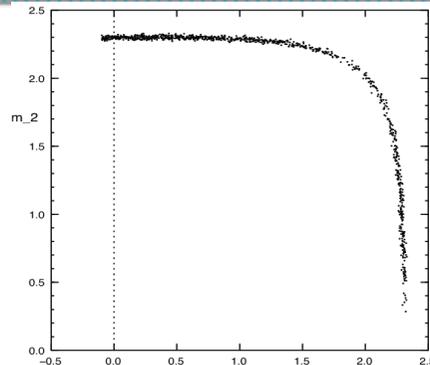
- Mixing is hard. Very many samples needed

# Bayesian Parametric bootstrap

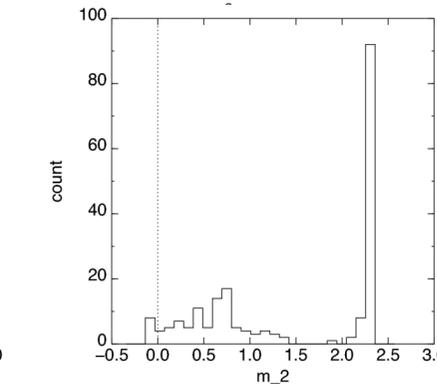
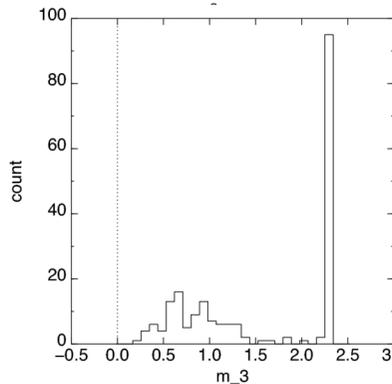
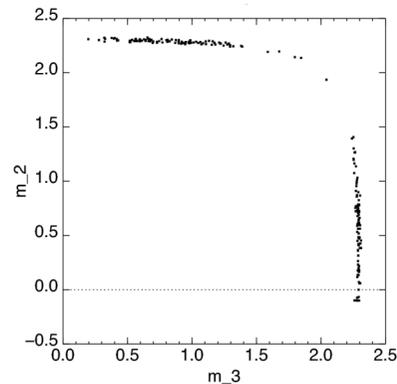
- *Randomized maximum likelihood* in some papers
- Bayesian priors treated as “extra data”
- Bootstrap data sets drawn from “best-fit” model, and MAP inversions found for each
- **Many** inversions needed. But avoids MCMC slow diffusion
- Jumps over parameter space very well



# Uncertainties upshot



MCMC



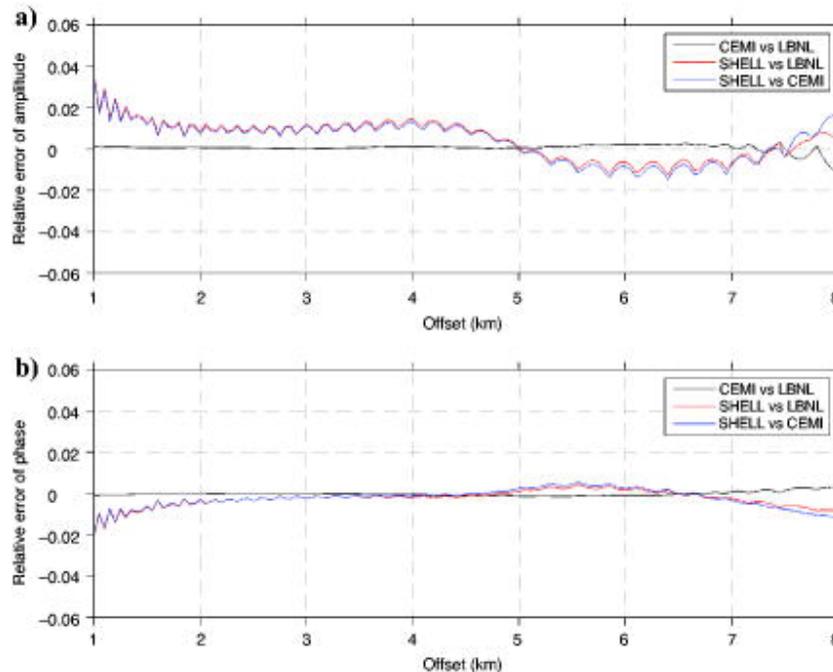
Bootstrap

- MCMC - expensive. Many forward runs
- Bootstrap - approx. but cheaper. Many inversions
- Either way: *very fast forward models needed*
  - But approximate forward models will increase the error, usually in a correlated way

# Example modelling errors (1)

3D FD/FE modelling:

Darnett et al , Geophysics 2007



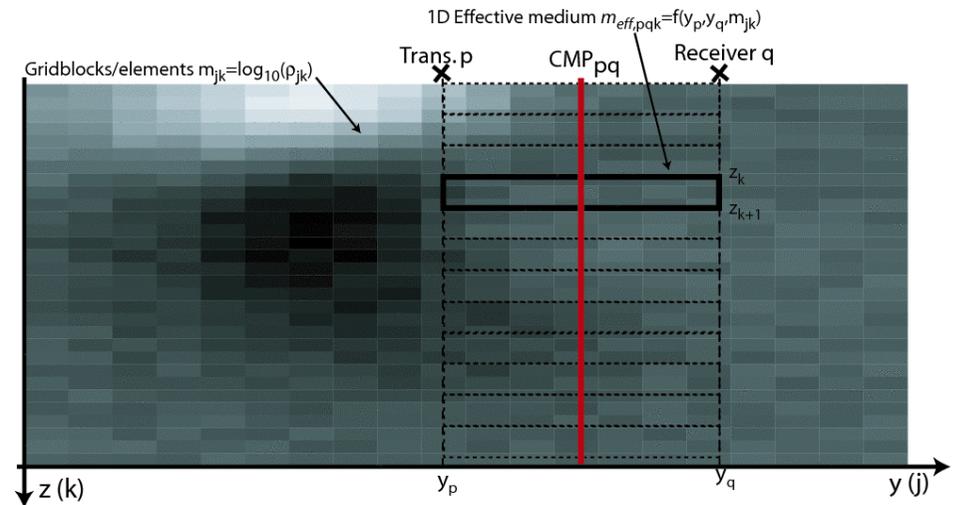
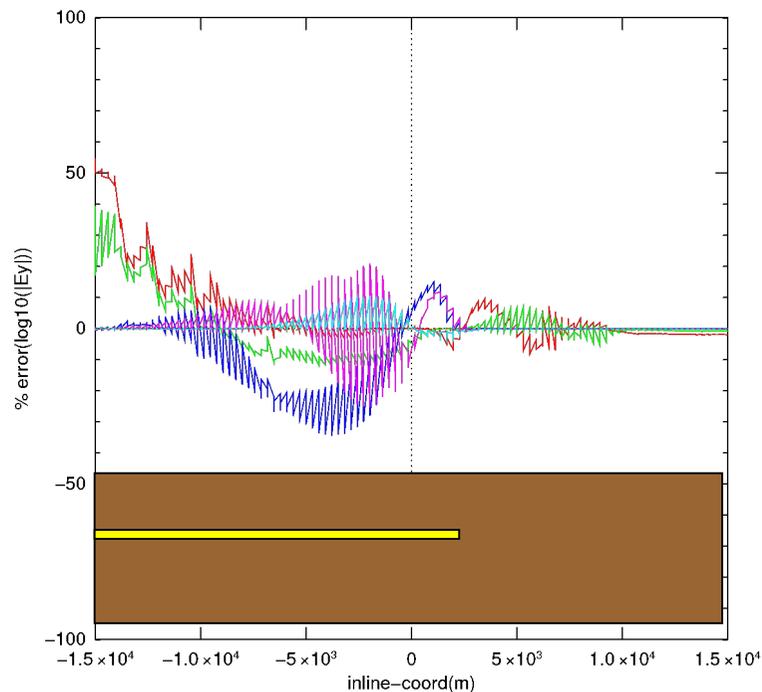
Note long correlations or trends in errors...

Errors probably below instrument errors ?

# Example modelling errors (2)

## 1D effective media CMP models

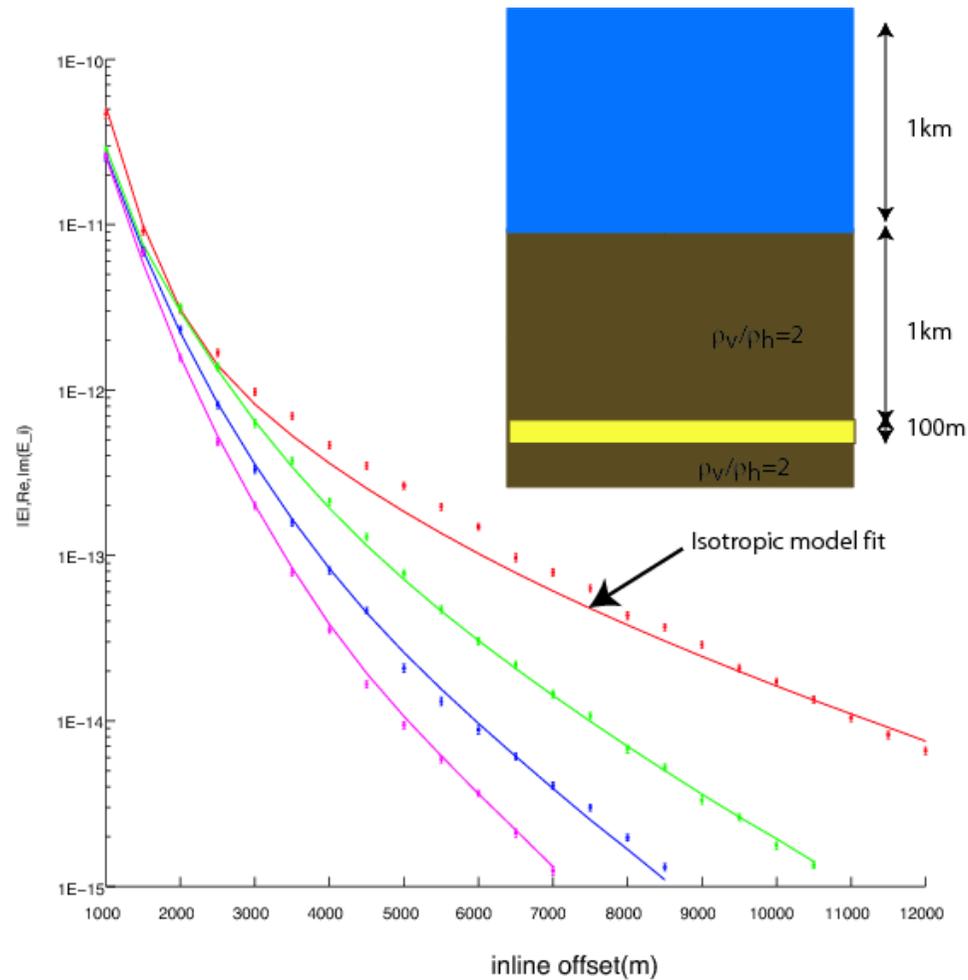
### Effective-media framework



Errors (modestly favourable case)

# Example modelling errors (3)

- Layering known, Anisotropy neglected



# Some things we know about model inference from linear theory

- OLS estimates ( $C_d$  “known”)

$$\begin{aligned}\hat{\mathbf{m}} &= (X^T C_d^{-1} X)^{-1} X^T C_d^{-1} y \\ \text{cov}(\hat{\mathbf{m}}) &= (X^T C_d^{-1} X)^{-1}\end{aligned}$$

Uncertainty depends on  $C_d$  at *leading* order

Robust components roughly independent of  $C_d$

- Assumed covariance  $C_d \rightarrow C_{\text{eff}}$

$$\begin{aligned}\hat{\mathbf{m}}' &= (X^T C_{\text{eff}}^{-1} X)^{-1} X^T C_{\text{eff}}^{-1} y \\ \text{cov}(\hat{\mathbf{m}}') &= (X^T C_{\text{eff}}^{-1} X)^{-1}\end{aligned}$$

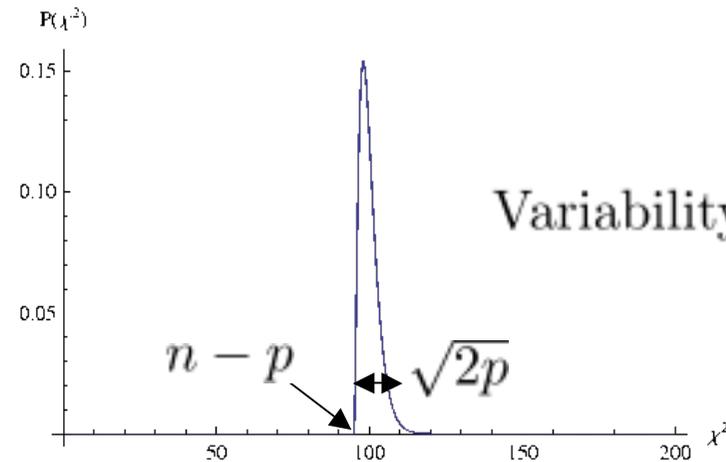
$$C_{\text{eff}} = \text{diag}\{\sigma_i^2\}$$

$$\text{so } X^T C_{\text{eff}}^{-1} X \sim O(n)$$

- $\hat{\mathbf{m}} \approx \hat{\mathbf{m}}'$  for ‘robust’ components (dominant eigenvalues of  $C_d$ )
- Bias mainly a problem if  $\text{cov}(\hat{\mathbf{m}}')$  gets too small

# Variability in $\chi^2$

$\chi^2 = (y - Xm)^T C_D^{-1} (y - Xm) \sim \chi_p^2$ , offset by  $n - p$  if noise 'correct'



What if we do ' $C_D$  known up to a scalar  $\sigma^2$ ...'

$$L(y|m) \sim \frac{\exp(-\frac{1}{2}(y - Xm)^T (\sigma^2 C_D)^{-1} (y - Xm))}{|\sigma^2 C_D|^{1/2}} \cdot \underbrace{\frac{1}{\sigma^2}}_{\text{Jeffreys}}$$

Then  $\text{std.dev}(\sigma^2) \sim 1/\sqrt{2\nu}$ , but still

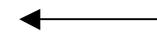
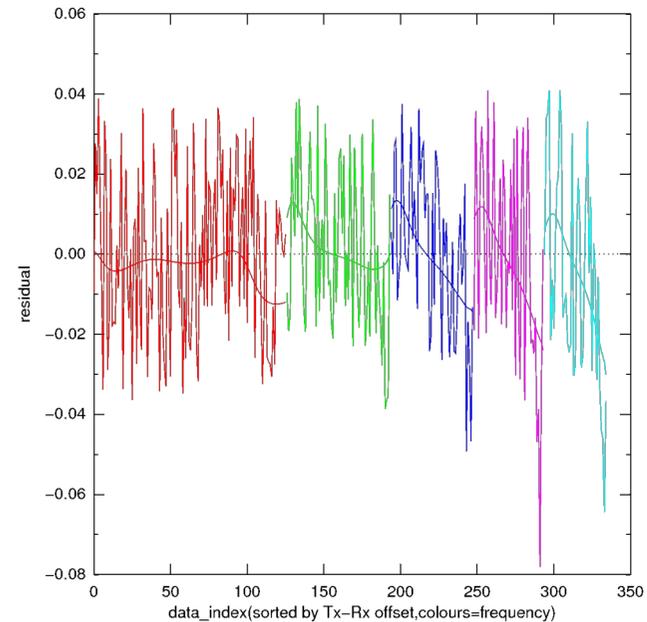
$$\chi_{\text{MS}}^2 = (y - Xm)^T C_D^{-1} (y - Xm) \sim F(p, n - p)$$

with asymptotic standard deviation

$$\text{std.dev}(\chi_{\text{MS}}^2) \sim \sqrt{2p}$$

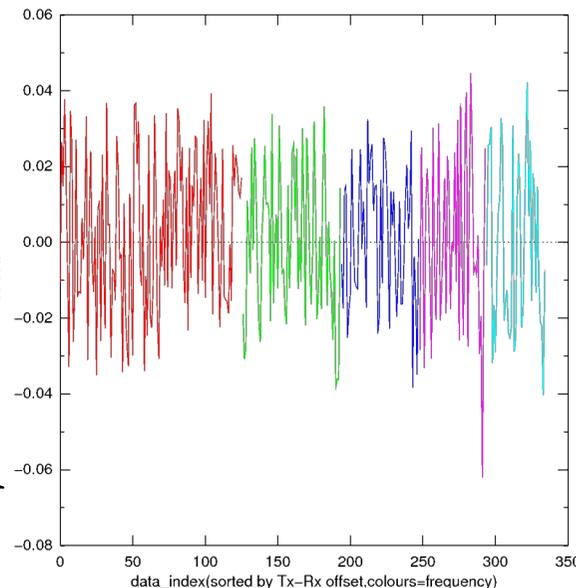
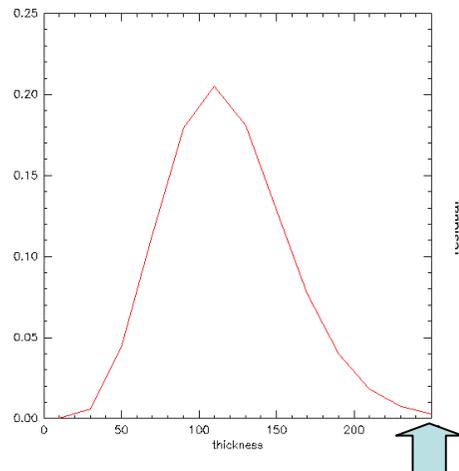
# Example problem and 3 approaches

- Test data set with residuals modified to give the effect of trend with offset
  - 250m thick resistor at 850m
- Inversion using zero-mean noise, posterior of thickness from marginalisation



Inversion gives thickness pdf with mean 110m, and 250m above upper 5% quantile.

Problem is *not* overfitted

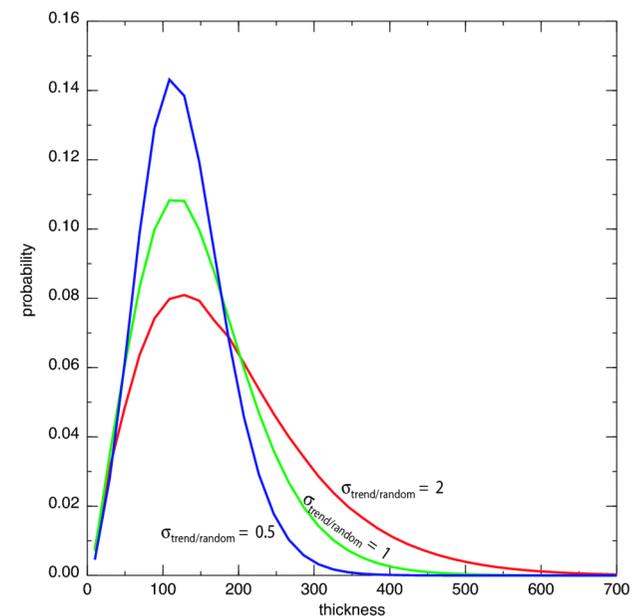
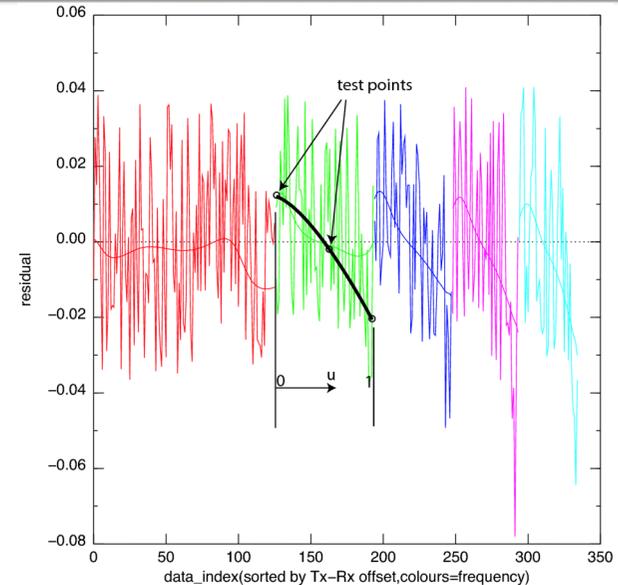


# 1) Explicit regression for trends/systematics

- noise="trend(u)+random"

$$\mathbf{y} = \mathbf{F}(\mathbf{m}) + \underbrace{C_d^{1/2} X}_{\equiv X_N} \cdot \mathbf{m}_n + \boldsymbol{\epsilon}$$

- Amounts to particular parametric forms of overall noise covariance
- User specifies form of trends, plus trend power/random power ratio
- Gaussian prior for  $\mathbf{m}_n$  comes from trend/power ratio
- Joint inversion for  $\mathbf{m}$  and  $\mathbf{m}_n$  (block-augmented Gauss-Newton framework)
- Probably too messy for effects that "thrash" (e.g.  $\text{Re}(E)$ ,  $\text{Im}(E)$ )



## 2) Effective data reduction

Toy problem inspiration: fit straight line to data  $y = Xm + \epsilon$  where

$$\epsilon_{\text{eff},i} = \rho\epsilon_0 + \sqrt{1 - \rho^2}\epsilon_i = \text{systematic} + \text{random}, \quad \rho^2 = \frac{\text{systematic power}}{\text{total noise power}}$$

So

$$C_D = \begin{pmatrix} 1 & \rho^2 & \rho^2 & \dots \\ \rho^2 & 1 & \rho^2 & \dots \\ \rho^2 & \rho^2 & 1 & \dots \\ \dots & \dots & \dots & \dots \\ \rho^2 & \rho^2 & \dots & 1 \end{pmatrix}$$

Then  $\text{cov}(\{\text{slope}, \text{intercept}\}) = (X^T C_D^{-1} X)^{-1}$ , and

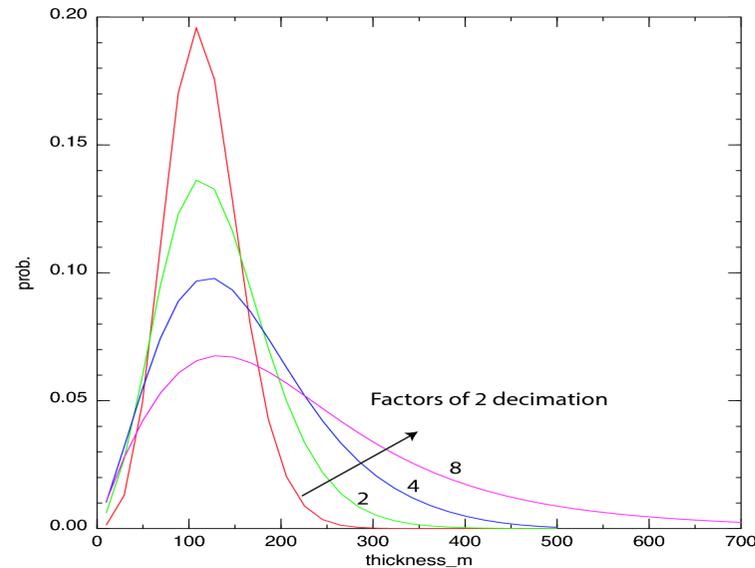
$$\text{std.dev}(\text{intercept}) \sim \sqrt{4/n + (1 - 4/n)\rho^2} \quad \text{flattens when } n = O(1/\rho^2)$$

Heuristic: inflate error bars as if  $n_{\text{eff}} = 1/\rho^2$ , i.e.  $\sigma_i \rightarrow \rho\sqrt{n}\sigma_i$ , so

$$(X^T C_{D,\text{eff}} X)^{-1} \rightarrow 1/\rho^2$$

## 2) Effective data reduction con't

- Test problem:



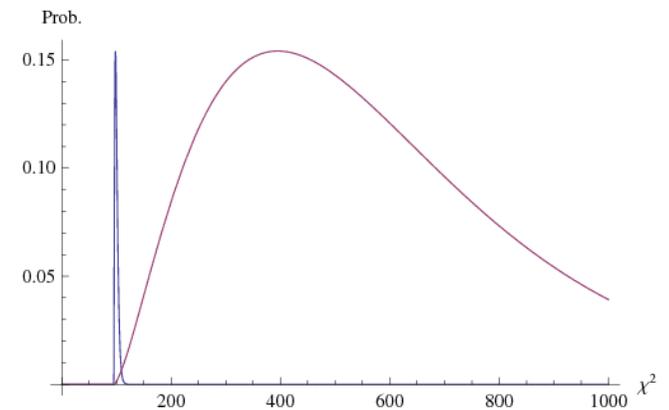
Limiting case  $\rho \rightarrow 1$ , where  $n_{\text{eff}} = 1$

$$L(y|m) \sim \exp(-\chi_{\text{RMS}}^2/2)$$

Upper bound provable from properties of the trace:  
if  $\epsilon$ =errors normalised by  $C_{ii}^{1/2}$

$$\epsilon^T C^{-1} \epsilon > \frac{1}{\text{tr}(C)} \|\epsilon\|^2 = \frac{\|\epsilon\|^2}{n}$$

$\therefore L$  is a 'bounding' likelihood



# 3) Averaging over the unknown noise covariance

- Use hierarchical model

$$p(\mathbf{m}|y) \sim N(y - F(\mathbf{m})|C)p(\mathbf{m})p(C)$$

- Inverse-Wishart prior

$$p(C) = \mathcal{W}^{-1}(\nu, C_0) = \frac{|\frac{1}{2}C^{-1}\nu C_0|^{\nu/2}}{Z_{\nu d}|C|^{(d+1)/2}} \exp(-\frac{\nu}{2}\text{tr}(C^{-1}C_0))$$

- mean

$$\langle C \rangle = \frac{\nu C_0}{\nu - d - 1}$$

- variance

$$\text{Var}(C_{ii}) = \frac{2\nu^2 C_{0,ii}^2}{(\nu - d - 1)^2(\nu - d - 3)}$$

- $\nu \sim$  “number of prior samples” in estimating  $C_0$

# Noise-covariance updating

- Given noise  $\delta\mathbf{y}$  and scatter matrix  $S$  (e.g. in Linear model):

$$\delta\mathbf{y} = \mathbf{y} - X\mathbf{m} \quad S = \delta\mathbf{y}\delta\mathbf{y}^T$$

- Covariance update

$$\begin{aligned}\pi(C, \delta\mathbf{y} | \nu, C_0) &\sim N(\delta\mathbf{y}, C) \mathcal{W}^{-1}(\nu C_0; \nu) \\ &\sim \mathcal{W}^{-1}(1 + \nu, S + \nu C_0)\end{aligned}$$

- Posterior mean is then

$$\langle C \rangle | \delta\mathbf{y} = (S + \nu C_0) / (1 + \nu - d - 1)$$

- This is an example of a “**shrinkage**” estimator: eigenvalues of  $S$  are squeezed towards those of  $C_0$

# Marginalising over unknown covariance

- Effective marginal posterior...

$$\begin{aligned}\pi(\mathbf{m}|\mathbf{y}, \nu, C_0) &\sim \int \pi(C, \delta\mathbf{y}|\nu, C_0) dC \sim \frac{|\nu C_0|^{\nu/2}}{|S + \nu C_0|^{(1+\nu)/2}} \\ &\sim \frac{1}{|I + \nu^{-1} C_0^{-1} S|^{(1+\nu)/2}} \sim \frac{1}{(1 + \chi^2(\mathbf{m})/\nu)^{(1+\nu)/2}}\end{aligned}$$

- Compare to known-noise case ( $\nu \rightarrow \infty$ )

$$\pi(\mathbf{m}|\mathbf{y}, C_D) \sim \exp(-\chi^2(\mathbf{m})/2)$$

# Marginalising for overall model evidence

- Laplace-like approximation...

$$\begin{aligned}\pi(\mathbf{y}|\nu, C_0) &\sim \int \frac{1}{(1 + \frac{1}{\nu}[\chi^2(\hat{\mathbf{m}}) + \frac{1}{2}(\mathbf{m} - \hat{\mathbf{m}})^T H(\mathbf{m} - \hat{\mathbf{m}})])^{(\nu+1)/2}} d\mathbf{m} \\ &\sim |H|^{-1/2} (1 + \chi^2(\hat{\mathbf{m}})/\nu)^{-(\nu-p+1)/2}\end{aligned}$$

- C.f. usual expression with known noise

$$\pi(\mathbf{y}|C_D) \sim |H|^{-1/2} \exp(-\chi^2(\hat{\mathbf{m}})/2)$$

- How to choose  $C_0$  and  $\nu$ ? Maximise marginal over free parameters  $C_0$  and  $\nu$ . Choose  $C_0$  from suitable subspace etc. Leads to EM algorithms (Chen '79 and followers)
- Findings:
  - Limitation  $\nu > d$  is annoying
  - Prior structure in  $C_0$  has strong influence and easy to mis-specify

# Everybody loves their Shrink(age) ....

- Stein (1975)

$S = U\Lambda U^T$  eigenvalue decomp.,  $d$  dimensions,  $N$  samples, with

$$C = U\Lambda'U^T$$

$$\lambda_i \rightarrow N\lambda_j / (N - d + 1 + 2\lambda_j \sum_{i \neq j} 1/(\lambda_j - \lambda_i))$$

Needs isotonizing. Also doesn't really work for  $N \ll d$

- Stein (1982), minimax ( $N = 1$ )

$$\lambda_i \rightarrow \frac{1}{2 + d - 2i} \lambda_i = \{\chi^2/d, 0, 0 \dots\}$$

...not invertible. Amounts to scaling all errors by  $\sqrt{d}$

- Haff (1980). Empirical Bayes. Extension to  $N = 1 < d$  by Ledoit (2001)

$$C = \frac{d-4}{d} \text{tr}(S)I + S/2$$

Invertible, but flattens all posterior model probabilities!

- Friedman (1989)...Leung (1998)

$$C = (1 - \alpha) \frac{\text{tr}(S)}{d} I + \alpha S$$

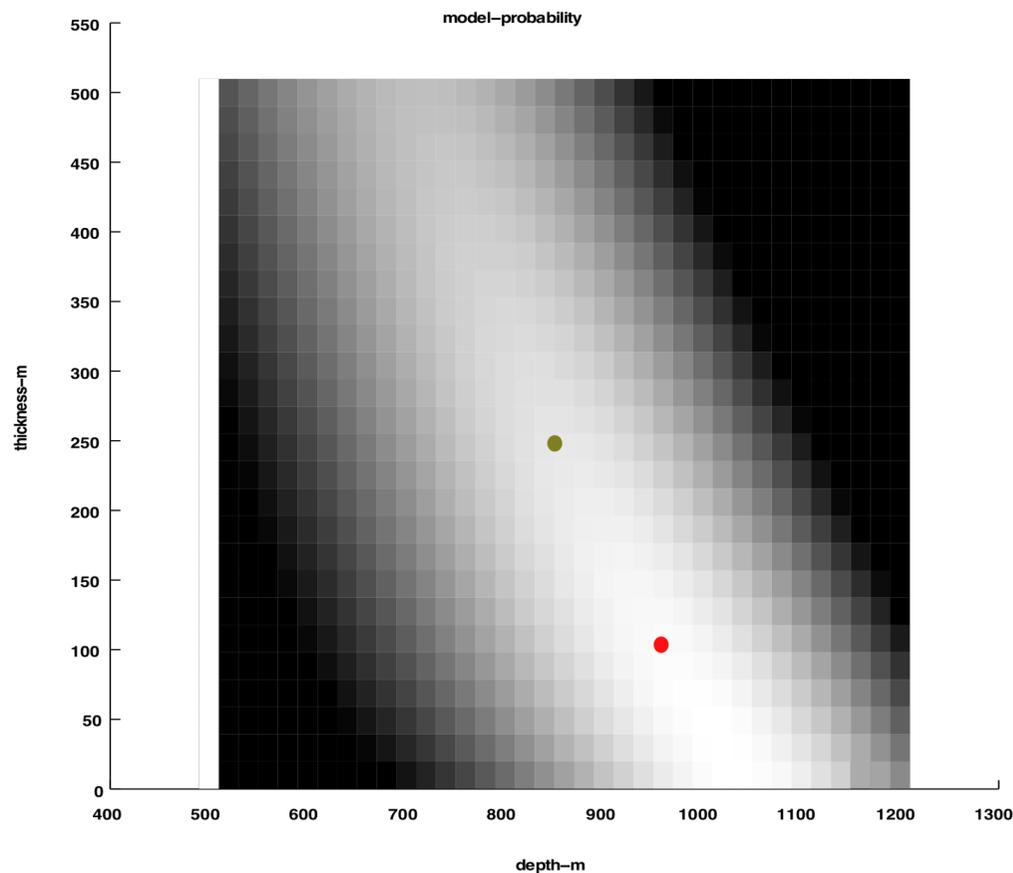
$\alpha$  from cross-validation (Friedman) or  $\alpha = N/(N + 2)$  (Leung, large  $N$ )

# Shrinkage on test problem

- Modified Friedman/Leung:

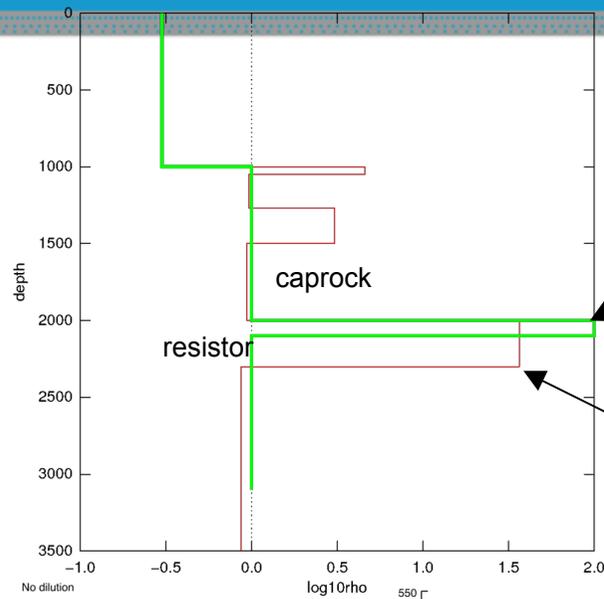
$$C = \alpha \frac{d}{\text{tr}(S)} S + (1 - \alpha) I$$

$\alpha =$  “fractional power non-random noise”



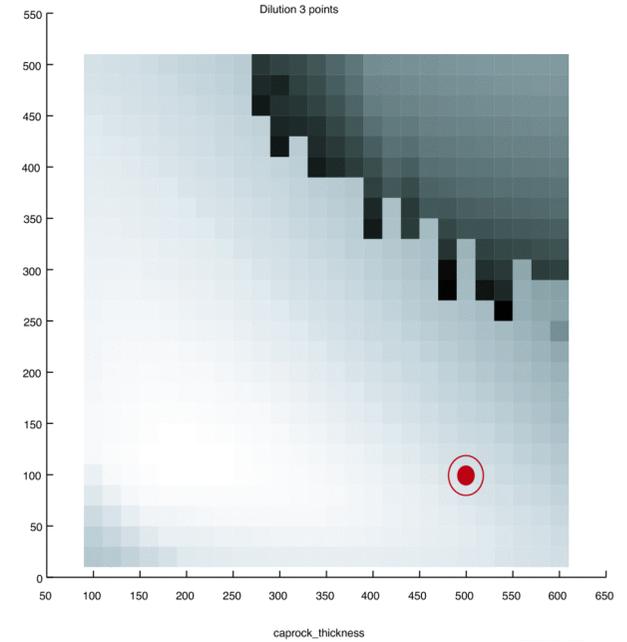
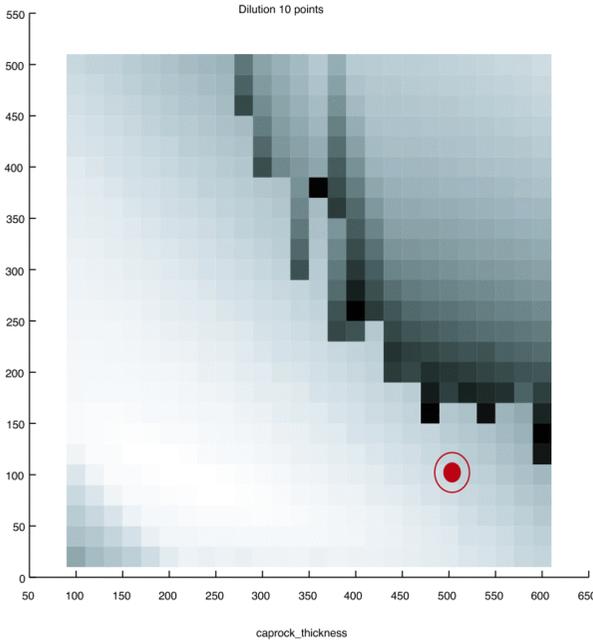
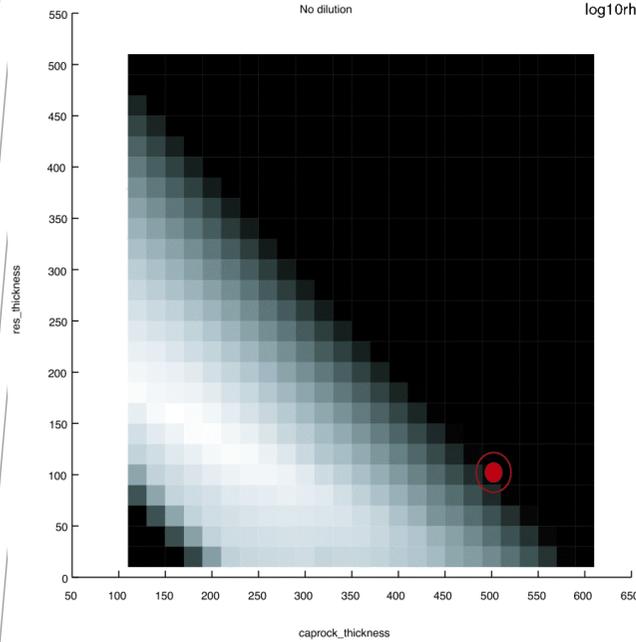
Calculation with  $\alpha=0.1$

# Anisotropy example again



truth case model

approx isotropic model



# Conclusions

- Independent Gaussian noise too optimistic given likely level of modelling noise, even in heavyweight codes.
- Explicit removal or error trends possible with extra systematic-trend parameters. Probably fragile.
- Error-bar inflation based on “RMS power” works, and easy to implement. Rather ad hoc theory
- Use of shrinkage probably a better theory. More obvious absorption of bias terms into covariance structure. Shrinkage fraction probably not inferable from data.